

**Search Notes**

Application/Control No.

10/665,496

Examiner

Frederick J. Parker

Applicant(s)/Patent under  
Reexamination

WEI ET AL.

Art Unit

1762

**SEARCHED**

| Class | Subclass | Date | Examiner |
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**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|             | DATE     | EXMR |
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| EAST update | 10/16/06 | JP   |
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